

LIST OF PRIOR ART CITED BY APPLICANT
(Filed on February 23, 2004)

Docket No. GK-OEH-178 / 500814.20080
 Applicant(s): Duc Chinc TRAN and Juergen KLEINSCHMIDT
 Application No.
 Filed: concurrently herewith -February 23, 2004

Group: 2851
 Examiner: Rutledge

U.S. PATENT DOCUMENTS

| Exam. Init | | Document Number | Date | Name | Class | Sub-Class | Filing Date Appropriate |
|------------|----|-----------------|------------|--------------------|-------|-----------|-------------------------|
| D.R. | AA | 6,359,969 | 03/19/2002 | Shmaenok | 378 | 156 | |
| D.R. | AB | 6,377,651 | 04/23/2002 | Richardson, et al. | 378 | 34 | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | CLASS | Sub-Class | Translation YES NO |
|------|----|-----------------|------------|---------|-------|-----------|--------------------|
| D.R. | AL | 102 15 469 | 11/06/2003 | Germany | — | — | US 2003/0190012 |
| | AM | | | | | | |
| | AN | | | | | | |
| | AO | | | | | | |
| | AP | | | | | | |
| | AQ | | | | | | |
| | AR | | | | | | |
| | AS | | | | | | |

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|------|----|---|
| D.R. | AV | Proceedings of SPIE, Vol. 4146 (2000) pgs. 128-131, Yamamoto et al. "Compact Debris Shutter Design of a laser-Produced Plasma Source for High NA Application" |
| | AW | |
| | AX | |
| | AY | |
| | AZ | |

Examiner: *Rutledge* Date: 3/6/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(2nd)LIST OF PRIOR ART CITED BY APPLICANT
(Filed on October 26, 2004)

Docket No. BK-OEH-178 / 500814.20080

Applicant(s): Duc Chinc TRAN and Juergen KLEINSCHMIDT

Application No. 10/784,438

Filed: February 23, 2004

Group: ~~783~~ 2851

Examiner: Rutledge

U.S. PATENT DOCUMENTS

| Exam. Init | | Document Number | Date | Name | Class | Sub-Class | Filing Date Appropriate |
|------------|----|-----------------|------------|----------------|-------|-----------|-------------------------|
| D.R. | AA | 6,285,737 | 09/04/2001 | Sweatt, et al. | 378 | 85 | |
| D.R. | AB | 2003/0020890 | 01/30/2003 | Ogushi, et al. | 355 | 53 | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | CLASS | Sub-Class | Translation YES NO |
|------|----|-----------------|------------|---------|-------|-----------|--------------------|
| D.R. | AL | WO 02/27406 | 04/04/2002 | WIPO | - | - | |
| D.R. | AM | 101 36 620 | 02/06/2003 | Germany | - | - | Abstract only |
| D.R. | AN | 101 28 284 | 02/27/2003 | Germany | - | - | Abstract only |
| | AO | | | | | | |
| | AP | | | | | | |
| | AQ | | | | | | |
| | AR | | | | | | |
| | AS | | | | | | |

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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| | AV | |
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| | AX | |
| | AY | |
| | AZ | |

Examiner: *[Signature]*

Date: 9/6/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.